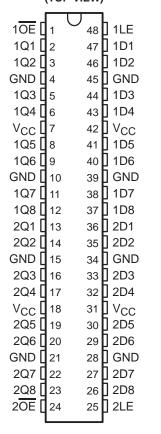
SCBS144K - MAY 1992 - REVISED APRIL 1999

- Members of the Texas Instruments Widebus™ Family
- State-of-the-Art Advanced BiCMOS Technology (ABT) Design for 3.3-V Operation and Low Static-Power Dissipation
- Support Mixed-Mode Signal Operation (5-V Input and Output Voltages With 3.3-V V_{CC})
- Support Unregulated Battery Operation Down to 2.7 V
- Typical V_{OLP} (Output Ground Bounce)
 < 0.8 V at V_{CC} = 3.3 V, T_A = 25°C
- I_{off} and Power-Up 3-State Support Hot Insertion
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Distributed V_{CC} and GND Pin Configuration Minimizes High-Speed Switching Noise
- Flow-Through Architecture Optimizes PCB Layout
- Latch-Up Performance Exceeds 500 mA Per JESD 17
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Package Options Include Plastic Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages and 380-mil Fine-Pitch Ceramic Flat (WD) Package Using 25-mil Center-to-Center Spacings

SN54LVTH16373 . . . WD PACKAGE SN74LVTH16373 . . . DGG OR DL PACKAGE (TOP VIEW)



description

The 'LVTH16373 devices are 16-bit transparent D-type latches with 3-state outputs designed for low-voltage (3.3-V) V_{CC} operation, but with the capability to provide a TTL interface to a 5-V system environment. These devices are particularly suitable for implementing buffer registers, I/O ports, bidirectional bus drivers, and working registers.

These devices can be used as two 8-bit latches or one 16-bit latch. When the latch-enable (LE) input is high, the Q outputs follow the data (D) inputs. When LE is taken low, the Q outputs are latched at the levels set up at the D inputs.



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description (continued)

A buffered output-enable (\overline{OE}) input can be used to place the eight outputs in either a normal logic state (high or low logic levels) or a high-impedance state. In the high-impedance state, the outputs neither load nor drive the bus lines significantly. The high-impedance state and the increased drive provide the capability to drive bus lines without interface or pullup components.

OE does not affect internal operations of the latch. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

When V_{CC} is between 0 and 1.5 V, the devices are in the high-impedance state during power up or power down. However, to ensure the high-impedance state above 1.5 V, \overline{OE} should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

These devices are fully specified for hot-insertion applications using I_{off} and power-up 3-state. The I_{off} circuitry disables the outputs, preventing damaging current backflow through the devices when they are powered down. The power-up 3-state circuitry places the outputs in the high-impedance state during power up and power down, which prevents driver conflict.

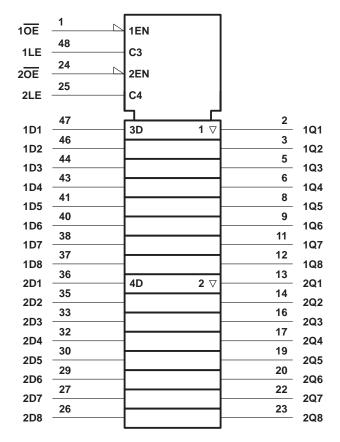
The SN54LVTH16373 is characterized for operation over the full military temperature range of –55°C to 125°C. The SN74LVTH16373 is characterized for operation from –40°C to 85°C.

FUNCTION TABLE (each 8-bit section)

	INPUTS						
ŌĒ	LE	D	Q				
L	Н	Н	Н				
L	Н	L	L				
L	L	Χ	Q ₀				
Н	Χ	Χ	Z				

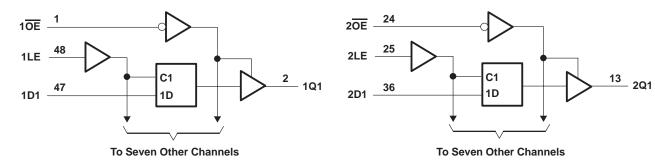


logic symbol†



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V _{CC}	0.5 V to 4.6 V
Input voltage range, V _I (see Note 1)	
Voltage range applied to any output in the high-impedance	
or power-off state, V _O (see Note 1)	–0.5 V to 7 V
Voltage range applied to any output in the high state, V _O (see Note 1)	
Current into any output in the low state, I _O : SN54LVTH16373	96 mA
SN74LVTH16373	128 mA
Current into any output in the high state, I _O (see Note 2): SN54LVTH16373	48 mA
SN74LVTH16373	64 mA
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I _{OK} (V _O < 0)	–50 mA
Package thermal impedance, θ _{JA} (see Note 3): DGG package	89°C/W
DL package	94°C/W
Storage temperature range, T _{stg}	–65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.
 - 2. This current flows only when the output is in the high state and $V_O > V_{CC}$.
 - 3. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 4)

						SN74LVTH16373		
		MIN	MAX	MIN	MAX	UNIT		
Vcc	Supply voltage	2.7	3.6	2.7	3.6	V		
VIH	High-level input voltage	2		2		V		
V _{IL}	Low-level input voltage		0.8		8.0	V		
VI	Input voltage		5.5		5.5	V		
loн	High-level output current		-24		-32	mA		
loL	Low-level output current			48		64	mA	
Δt/Δν	Input transition rise or fall rate	Outputs enabled		10		10	ns/V	
Δt/ΔV _{CC}	Power-up ramp rate	200		200		μs/V		
T _A	Operating free-air temperature	-55	125	-40	85	°C		

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.



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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS			4LVTH16	6373	SN7	4LVTH16	373	LIAUT				
PAI	RAMETER	lESI C	ONDITIONS	MIN	TYP†	MAX	MIN	TYP†	MAX	UNIT				
VIK	$V_{CC} = 2.7 \text{ V}, \qquad I_{I} = -18 \text{ mA}$		I _I = -18 mA			-1.2			-1.2	V				
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V},$	I _{OH} = -100 μA	V _{CC} -0	.2		V _{CC} -0	.2						
VOH		$V_{CC} = 2.7 \text{ V},$	I _{OH} = -8 mA	2.4			2.4			V				
, vOH		V _{CC} = 3 V	$I_{OH} = -24 \text{ mA}$	2						v				
		VCC = 3 V	$I_{OH} = -32 \text{ mA}$				2							
		V _{CC} = 2.7 V	I _{OL} = 100 μA			0.2			0.2	.2				
		VCC = 2.7 V	I _{OL} = 24 mA			0.5			0.5					
VOL			I _{OL} = 16 mA			0.4			0.4	V				
VOL		V _{CC} = 3 V	I _{OL} = 32 mA			0.5			0.5	V				
		VCC = 3 V	$I_{OL} = 48 \text{ mA}$			0.55								
			I _{OL} = 64 mA						0.55	<u> </u>				
		$V_{CC} = 0 \text{ or } 3.6 \text{ V},$	V _I = 5.5 V			10			10					
ΙΙ	Control inputs	$V_{CC} = 3.6 \text{ V},$	$V_I = V_{CC}$ or GND			±1			±1	μΑ				
''	Doto inputo	VCC = 3.6 V	VI = VCC			1			1	μΑ				
	Data inputs		V _I = 0			-5			- 5					
l _{off}		$V_{CC} = 0$,	V_I or $V_O = 0$ to 4.5 V						±100	μΑ				
	Data inputs	V _{CC} = 3 V	V _I = 0.8 V	75			75			μΑ				
l(hold)			V _I = 2 V	-75			-75							
i(ilola)		$V_{CC} = 3.6 V^{\ddagger}$	$V_{I} = 0 \text{ to } 3.6 \text{ V}$						500 -750					
lozh		$V_{CC} = 3.6 \text{ V},$	V _O = 3 V			5			5	μΑ				
lozL		$V_{CC} = 3.6 \text{ V},$	$V_0 = 0.5 V$			-5			– 5	μΑ				
I _{OZPU}		$\frac{V_{CC}}{OE} = 0$ to 1.5 V, $V_{O} = 0$	0.5 V to 3 V,			±100*			±100	μΑ				
lozpd		$\frac{\text{VCC}}{\text{OE}}$ = 1.5 V to 0, V _O = 0.5 V to 3 V, $\frac{\text{OE}}{\text{OE}}$ = don't care				±100*			±100	μА				
ICC		V _{CC} = 3.6 V,	Outputs high			0.19			0.19					
		$I_{O} = 0,$	Outputs low		5				5	mA				
<u></u>		$V_I = V_{CC}$ or GND	Outputs disabled			0.19			0.19					
Δl _{CC} §		V_{CC} = 3 V to 3.6 V, One input at V_{CC} – 0.6 V, Other inputs at V_{CC} or GND				0.2			0.2	mA				
Ci		V _I = 3 V or 0			3			3		рF				
Co		V _O = 3 V or 0			9			9		pF				
			•			-								

^{*} On products compliant to MIL-PRF-38535, this parameter is not production tested.



[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C. ‡ This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

[§] This is the increase in supply current for each input that is at the specified TTL voltage level rather than VCC or GND.

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timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figure 1)

				SN54LVTH16373				SN74LVTH16373				
			V _{CC} = 3 ± 0.3		3.3 V 3 V	V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		V _{CC} = 2.7 V		UNIT
		MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX			
t _W	Pulse duration, LE high	3		3		3		3		ns		
t _{su}	Setup time, data before LE↓	2		2		1		0.6		ns		
th	Hold time, data after LE↓	3		3.3		1		1.1		ns		

switching characteristics over recommended operating free-air temperature range, C_L = 50 pF (unless otherwise noted) (see Figure 1)

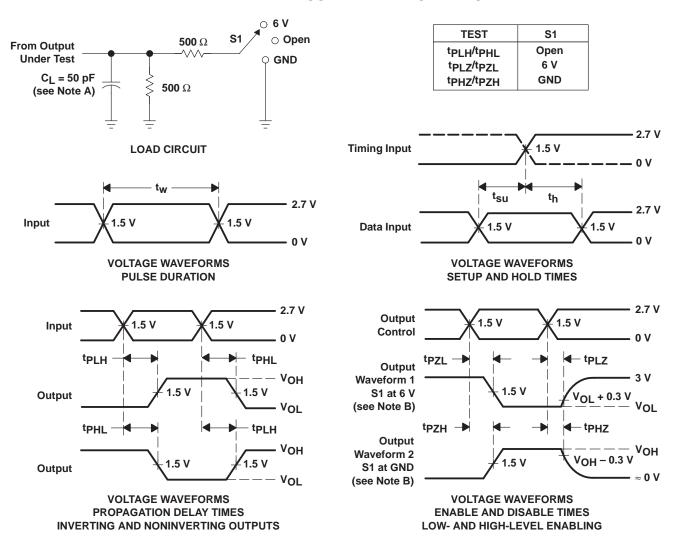
		TO (OUTPUT)	SN54LVTH16373									
PARAMETER	FROM (INPUT)		V _{CC} = 3.3 V ± 0.3 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V			V _{CC} = 2.7 V		UNIT
			MIN	MAX	MIN	MAX	MIN	TYP [†]	MAX	MIN	MAX	
^t PLH	D	Q	1.4	4.5		5.2	1.5	2.7	3.8		4.2	ns
^t PHL	D	Q	1.4	4.4		4.8	1.5	2.5	3.6		4	115
^t PLH	LE	Q	1.8	5.5		5.8	2.1	3	4.3		4.8	ns
^t PHL	LE	ď	1.8	5.2		5.6	2.1	2.9	4		4	115
^t PZH	ŌĒ	Q	1.4	5.7		6.7	1.5	2.8	4.3		5.1	ns
^t PZL	OE	Q	1.4	5.5		6	1.5	2.8	4.3		4.7	115
^t PHZ	ŌĒ	Q	2	6		6.2	2.4	3.5	5		5.4	ns
t _{PLZ}) OE	l q	1.4	5.2		5.6	2	3.2	4.7		4.8	115
^t sk(o)									0.5			ns

[†] All typical values are at $V_{CC} = 3.3 \text{ V}$, $T_A = 25^{\circ}\text{C}$.



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PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_O = 50 \ \Omega$, $t_f \leq 2.5 \ ns$, $t_f \leq 2.5 \ ns$.
- D. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

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